

**Features**

- Function, pinout, and drive compatible with FCT, F logic
- FCT-C speed at 4.1 ns max. (Com'l), FCT-A speed at 4.6 ns max. (Com'l)
- Reduced  $V_{OH}$  (typically = 3.3V) versions of equivalent FCT functions
- Edge-rate control circuitry for significantly improved noise characteristics
- Power-off disable feature
- ESD > 2000V

**Matched rise and fall times**

- Fully compatible with TTL input and output logic levels

• Sink current	64 mA (Com'l), 48 mA (Mil)
Source current	32 mA (Com'l), 12 mA (Mil)

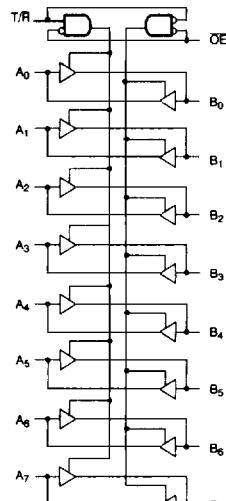
**Functional Description**

The FCT245T contains eight non-inverting bidirectional buffers with three-state outputs and is intended for bus oriented applications. For the

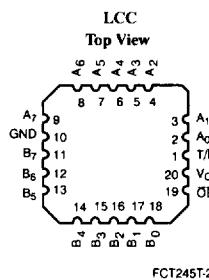
FCT245T, current sinking capability is 64 mA at the A and B ports.

The Transmit/Receiver ( $T/R$ ) input determines the direction of data flow through bidirectional transceiver. Transmit (Active HIGH) enables data from A ports to B ports. The output enable ( $OE$ ), when HIGH, disables both the A and B ports by putting them in a High Z condition.

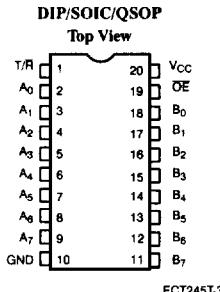
The outputs are designed with a power-off disable feature to allow for live insertion of boards.

**Logic Block Diagram**


FCT245T-1

**Pin Configurations**


FCT245T-2



FCT245T-3

**Function Table<sup>[1]</sup>**

OE	T/R	Operation
L	L	B Data to Bus A
L	H	A Data to Bus B
H	X	High Z State

**Note:**

1. H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care.

**Maximum Ratings<sup>[2, 3]</sup>**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....	-65°C to +150°C
Ambient Temperature with Power Applied .....	-65°C to +135°C
Supply Voltage to Ground Potential .....	-0.5V to +7.0V
DC Input Voltage .....	-0.5V to +7.0V
DC Output Voltage .....	-0.5V to +7.0V
DC Output Current (Maximum Sink Current/Pin) .....	120 mA
Power Dissipation .....	0.5W

Static Discharge Voltage ..... >2001V  
(per MIL-STD-883, Method 3015)

**Operating Range**

Range	Range	Ambient Temperature	V <sub>CC</sub>
Commercial	CT, DT	0°C to +70°C	5V ± 5%
Commercial	T, AT	-40°C to +85°C	5V ± 5%
Military <sup>[4]</sup>	All	-55°C to +125°C	5V ± 10%

**Electrical Characteristics Over the Operating Range**

Parameter	Description	Test Conditions		Min.	Typ. <sup>[5]</sup>	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> =Min., I <sub>OH</sub> = -32 mA	Com'l	2.0			V
		V <sub>CC</sub> =Min., I <sub>OH</sub> = -15 mA	Com'l	2.4	3.3		V
		V <sub>CC</sub> =Min., I <sub>OH</sub> = -12 mA	Mil	2.4	3.3		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> =Min., I <sub>OL</sub> =64 mA	Com'l		0.3	0.55	V
		V <sub>CC</sub> =Min., I <sub>OL</sub> =48mA	Mil		0.3	0.55	V
V <sub>IH</sub>	Input HIGH Voltage			2.0			V
V <sub>IL</sub>	Input LOW Voltage					0.8	V
V <sub>H</sub>	Hysteresis <sup>[6]</sup>	All inputs			0.2		V
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> =Min., I <sub>IN</sub> = -18 mA			-0.7	-1.2	V
I <sub>I</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>IN</sub> =V <sub>CC</sub>				5	µA
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>IN</sub> =2.7V				±1	µA
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> =Max., V <sub>IN</sub> =0.5V				±1	µA
I <sub>OS</sub>	Output Short Circuit Current <sup>[7]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =0.0V		-60	-120	-225	mA
I <sub>OFF</sub>	Power-Off Disable	V <sub>CC</sub> =0V, V <sub>OUT</sub> =4.5V				±1	µA

**Capacitance<sup>[6]</sup>**

Parameter	Description	Typ. <sup>[5]</sup>	Max.	Unit
C <sub>IN</sub>	Input Capacitance	5	10	pF
C <sub>OUT</sub>	Output Capacitance	9	12	pF

**Notes:**

2. Unless otherwise noted, these limits are over the operating free-air temperature range.
3. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V<sub>CC</sub> or ground.
4. T<sub>A</sub> is the "instant on" case temperature.
5. Typical values are at V<sub>CC</sub>=5.0V, T<sub>A</sub>=+25°C ambient.
6. This parameter is guaranteed but not tested.
7. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

**Power Supply Characteristics**

Parameter	Description	Test Conditions	Typ. <sup>[5]</sup>	Max.	Unit
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>CC</sub> =Max., V <sub>IN</sub> ≤0.2V, V <sub>IN</sub> ≥V <sub>CC</sub> -0.2V	0.1	0.2	mA
ΔI <sub>CC</sub>	Quiescent Power Supply Current (TTL inputs HIGH)	V <sub>CC</sub> =Max., V <sub>IN</sub> =3.4V, <sup>[8]</sup> f <sub>i</sub> =0, Outputs Open	0.5	2.0	mA
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>[9]</sup>	V <sub>CC</sub> =Max., One Input Toggling, 50% Duty Cycle, Outputs Open, T/R or OE=GND and V <sub>IN</sub> ≤0.2V or V <sub>IN</sub> ≥V <sub>CC</sub> -0.2V	0.06	0.12	mA/ MHz
I <sub>C</sub>	Total Power Supply Current <sup>[10]</sup>	V <sub>CC</sub> =Max., 50% Duty Cycle, Outputs Open, One Bit Toggling at f <sub>i</sub> =10 MHz, T/R or OE=GND and V <sub>IN</sub> ≤0.2V or V <sub>IN</sub> ≥V <sub>CC</sub> -0.2V	0.7	1.4	mA
		V <sub>CC</sub> =Max., 50% Duty Cycle, Outputs Open, One Bit Toggling at f <sub>i</sub> =10 MHz, T/R or OE=GND and V <sub>IN</sub> =3.4V or V <sub>IN</sub> =GND	1.2	3.4	mA
		V <sub>CC</sub> =Max., 50% Duty Cycle, Outputs Open, Eight Bits Toggling at f <sub>i</sub> =2.5 MHz, T/R or OE=GND and V <sub>IN</sub> ≤0.2V or V <sub>IN</sub> ≥V <sub>CC</sub> -0.2V	1.3	2.6 <sup>[11]</sup>	mA
		V <sub>CC</sub> =Max., 50% Duty Cycle, Outputs Open, Eight Bits Toggling at f <sub>i</sub> =2.5 MHz, T/R or OE=GND and V <sub>IN</sub> =3.4V or V <sub>IN</sub> =GND	3.3	10.6 <sup>[11]</sup>	mA

**Notes:**

8. Per TTL driven input (V<sub>IN</sub>=3.4V); all other inputs at V<sub>CC</sub> or GND.  
 9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.  
 10. I<sub>C</sub> = I<sub>QUIESCENT</sub> + I<sub>INPUTS</sub> + I<sub>DYNAMIC</sub>  
     I<sub>C</sub> = I<sub>CC</sub>+ΔI<sub>CC</sub>D<sub>H</sub>N<sub>T</sub>+I<sub>CCD</sub>(f<sub>0</sub>/2 + f<sub>i</sub>N<sub>1</sub>)  
     I<sub>CC</sub> = Quiescent Current with CMOS input levels  
     ΔI<sub>CC</sub> = Power Supply Current for a TTL HIGH input  
           (V<sub>IN</sub>=3.4V)  
     D<sub>H</sub> = Duty Cycle for TTL inputs HIGH

- N<sub>T</sub> = Number of TTL inputs at D<sub>H</sub>  
 I<sub>CCD</sub> = Dynamic Current caused by an input transition pair  
       (HLH or LHL)  
 f<sub>0</sub> = Clock frequency for registered devices, otherwise zero  
 f<sub>i</sub> = Input signal frequency  
 N<sub>1</sub> = Number of inputs changing at f<sub>i</sub>  
 All currents are in millamps and all frequencies are in megahertz.  
 11. Values for these conditions are examples of the I<sub>CC</sub> formula. These limits are guaranteed but not tested.



CYPRESS

CY54/74FCT245T

## Switching Characteristics Over the Operating Range

Parameter	Description	FCT245T				FCT245AT				Unit	Fig. No. <sup>[13]</sup>		
		Military		Commercial		Military		Commercial					
		Min. <sup>[12]</sup>	Max.										
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay A to B or B to A	1.5	7.5	1.5	7.0	1.5	4.9	1.5	4.6	ns	1, 3		
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable Time OE or T/R to A or B	1.5	10.0	1.5	9.5	1.5	6.5	1.5	6.2	ns	1, 7, 8		
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable Time OE or T/R to A or B	1.5	10.0	1.5	7.5	1.5	6.0	1.5	5.0	ns	1, 7, 8		

## Switching Characteristics Over the Operating Range

Parameter	Description	FCT245CT				FCT245DT		Unit	Fig. No. <sup>[13]</sup>		
		Military		Commercial		Commercial					
		Min. <sup>[12]</sup>	Max.	Min. <sup>[12]</sup>	Max.	Min. <sup>[12]</sup>	Max.				
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay A to B or B to A	1.5	4.5	1.5	4.1	1.5	3.8	ns	1, 3		
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable Time OE or T/R to A or B	1.5	6.2	1.5	5.8	1.5	5.0	ns	1, 7, 8		
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable Time OE or T/R to A or B	1.5	5.2	1.5	4.8	1.5	4.3	ns	1, 7, 8		

Shaded areas contain preliminary information.

## Notes:

12. Minimum limits are guaranteed but not tested on Propagation Delays.  
 13. See "Parameter Measurement Information" in the General Information Section.

**Ordering Information**

<b>Speed (ns)</b>	<b>Ordering Code</b>	<b>Package Name</b>	<b>Package Type</b>	<b>Operating Range</b>
3.8	CY74FCT245DTQC	Q5	20-Lead (150-Mil) QSOP	Commercial
	CY74FCT245DTSOC	S5	20-Lead (300-Mil) Molded SOIC	
4.1	CY74FCT245CTPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT245CTQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT245CTSOC	S5	20-Lead (300-Mil) Molded SOIC	
4.5	CY54FCT245CTDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT245CTLMB	L61	20-Square Leadless Chip Carrier	
4.6	CY74FCT245ATPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT245ATQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT245ATSOC	S5	20-Lead (300-Mil) Molded SOIC	
4.9	CY54FCT245ATDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT245ATLMB	L61	20-Square Leadless Chip Carrier	
7.0	CY74FCT245TPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT245TQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT245TSOC	S5	20-Lead (300-Mil) Molded SOIC	
7.5	CY54FCT245TDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT245TLMB	L61	20-Square Leadless Chip Carrier	

Shaded areas contain preliminary information.

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